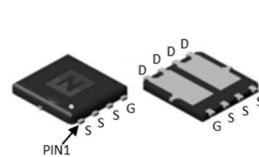
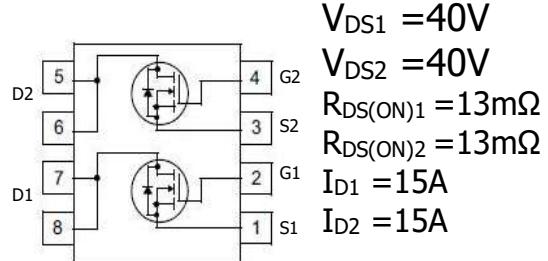



**• General Description**

It combines trench MOSFET technology with a low resistance package to provide extremely low  $R_{DS(ON)}$ . This device is ideal for load switch and battery protection applications.

**• Features**

- Advance high cell density Trench technology
- Low  $R_{DS(ON)}$  to minimize conductive loss
- Low Gate Charge for fast switching
- Dual DIE in one package

**• Product Summary**

**• Application**

- Synchronous Rectification in DC/DC and AC/DC Converters
- Industrial and Motor Drive applications

DFN3\*3

**• Ordering Information:**

Part NO.	ZMD68403M		
Marking	68403		
Packing Information	REEL TAPE		
Basic ordering unit (pcs)	5000		

**• Absolute Maximum Ratings ( $T_c = 25^\circ C$ )**

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	40	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$I_D @ T_c = 25^\circ C$	15	A
	$I_D @ T_c = 75^\circ C$	11	A
	$I_D @ T_c = 100^\circ C$	9	A
Pulsed Drain Current <sup>(1)</sup>	$I_{DM}$	45	A
Total Power Dissipation	$P_D @ T_c = 25^\circ C$	29	W
Total Power Dissipation	$P_D @ T_A = 25^\circ C$	1.7	W
Operating Junction Temperature	$T_J$	-55 to 150	$^\circ C$
Storage Temperature	$T_{STG}$	-55 to 150	$^\circ C$



Single Pulse Avalanche Energy (L=0.5mH,V <sub>GS</sub> =10V,R <sub>g</sub> =25Ω,T <sub>J</sub> =25°C)	E <sub>AS</sub>	85	mJ
Single Pulse Avalanche Energy (L=0.1mH,V <sub>GS</sub> =10V,R <sub>g</sub> =25Ω,T <sub>J</sub> =25°C)	E <sub>AS</sub>	34	mJ

**•Thermal resistance**

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal resistance, junction - case	R <sub>thJC</sub>	-	-	4.2	° C/W
Thermal resistance, junction - ambient	R <sub>thJA</sub>	-	-	70	° C/W
Soldering temperature, wavesoldering for 10s	T <sub>sold</sub>	-	-	265	° C

**•Electronic Characteristics**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	40			V
Gate Threshold Voltage	V <sub>GS(TH)</sub>	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	1.2		2.5	V
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =40V, V <sub>GS</sub> =0V			1.0	uA
Gate- Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V			±100	nA
Static Drain-source On Resistance	R <sub>DSS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =10A		13	18	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =8A		18	23	mΩ
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> =25V, I <sub>D</sub> =4A		6		s

**•Dynamic Characteristics**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Input capacitance	C <sub>iss</sub>	f = 1MHz V <sub>DS</sub> =25V	-	1490	-	pF
Output capacitance	C <sub>oss</sub>		-	110	-	
Reverse transfer capacitance	C <sub>rss</sub>		-	80	-	
Total gate charge	Q <sub>g</sub>	V <sub>DD</sub> =25V I <sub>D</sub> = 20A V <sub>GS</sub> = 10V	-	21	-	nC
Gate - Source charge	Q <sub>gs</sub>		-	3.8	-	
Gate - Drain charge	Q <sub>gd</sub>		-	4.2	-	
Turn-ON Delay time	t <sub>D(on)</sub>	V <sub>GS</sub> =10V, V <sub>DS</sub> =15V R <sub>G</sub> =3.3Ω, I <sub>D</sub> =20A		6		ns
Turn-ON Rise time	t <sub>r</sub>			2.0		ns
Turn-Off Delay time	t <sub>D(off)</sub>			34		ns
Turn-Off Fall time	t <sub>f</sub>			5.5		ns



## Diode Characteristics

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Reverse Recovery Time	$t_{RR}$	$V_{DD} = 20 \text{ V}, dI_s/dt = 100 \text{ A/us}, I_s = 30\text{A}$		8		ns
Reverse Recovery Charge	$Q_{RR}$			17		ns

Note: ① Pulse Test : Pulse width  $\leq 300\mu\text{s}$ , Duty cycle  $\leq 2\%$  ;

Fig.1 Power Dissipation

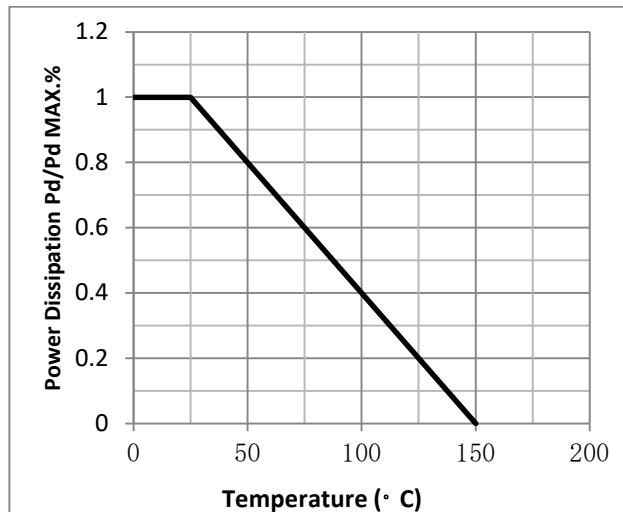


Fig.2 Typical output Characteristics

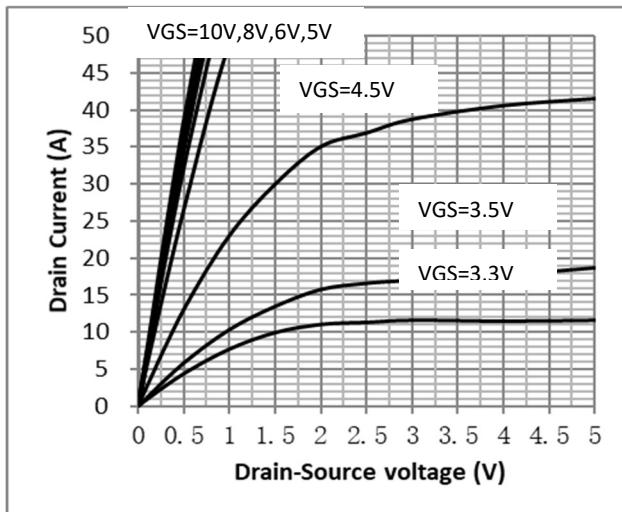


Fig.3 Threshold Voltage V.S Junction Temperature

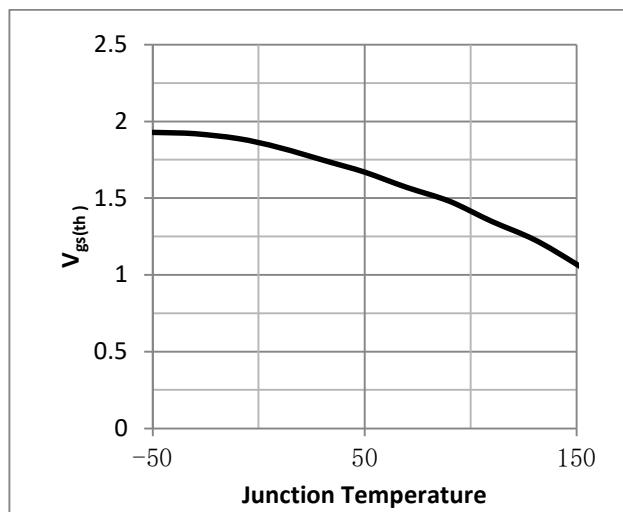


Fig.4 Resistance V.S Drain Current

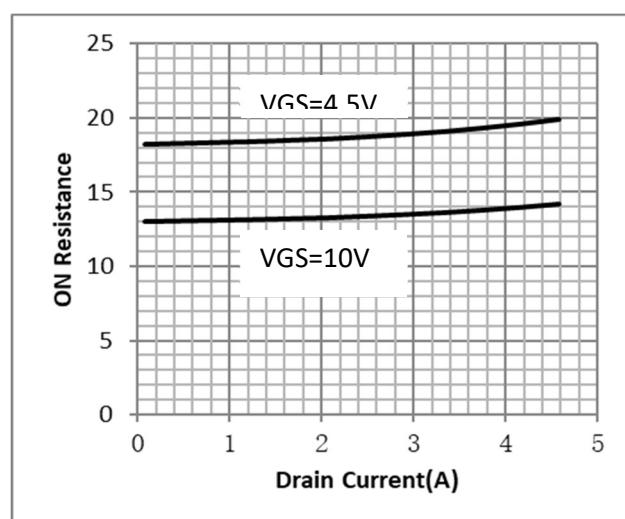




Fig.5 On-Resistance VS Gate Source Voltage

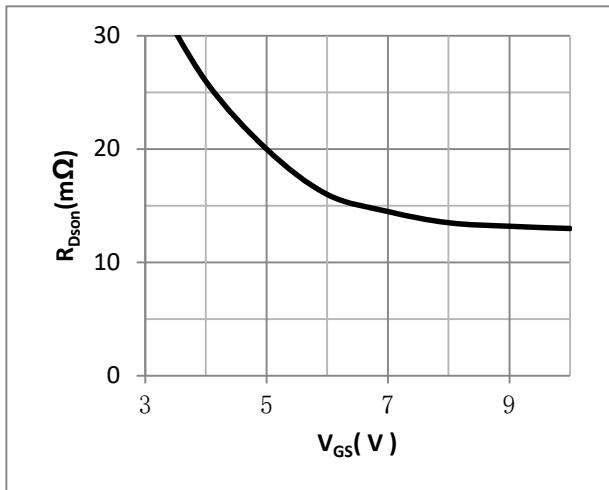


Fig.6 On-Resistance V.S Junction Temperature

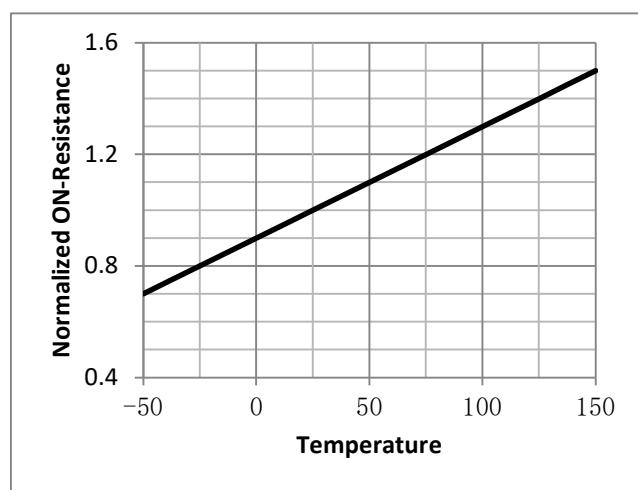


Figure 7. Diode Forward Voltage vs. Current

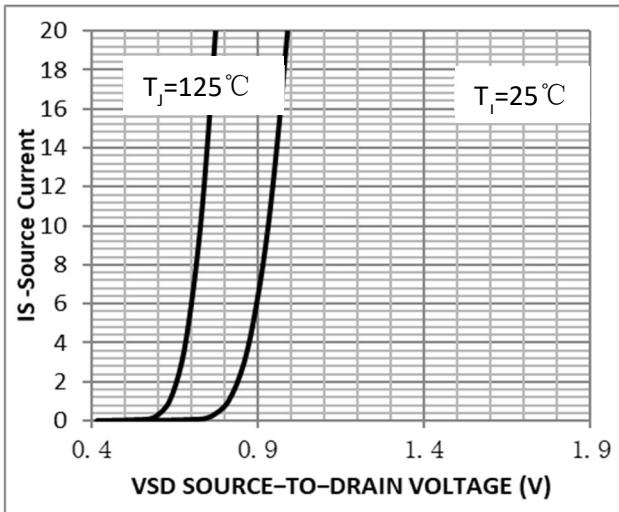


Figure 8. Transfer Characteristics

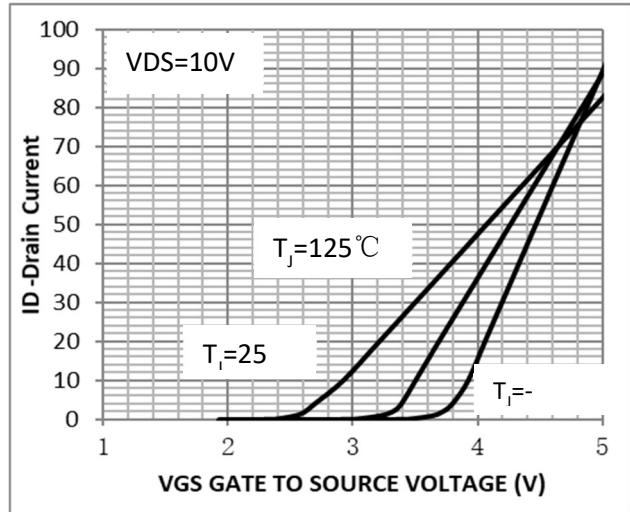


Fig.9 SOA Maximum Safe Operating Area

Fig.10 ID-Junction Temperature

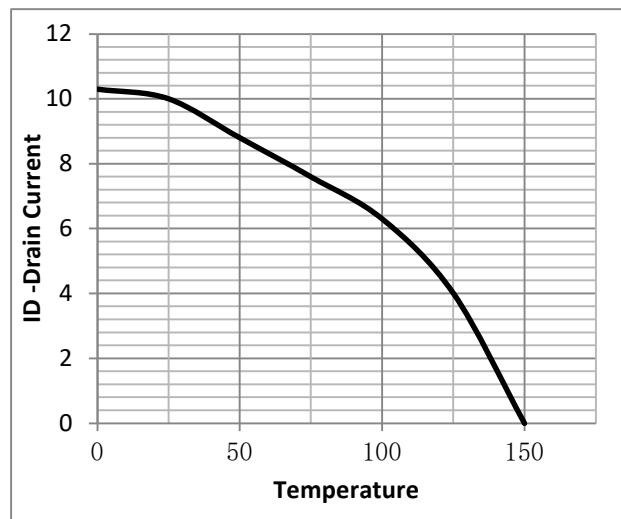
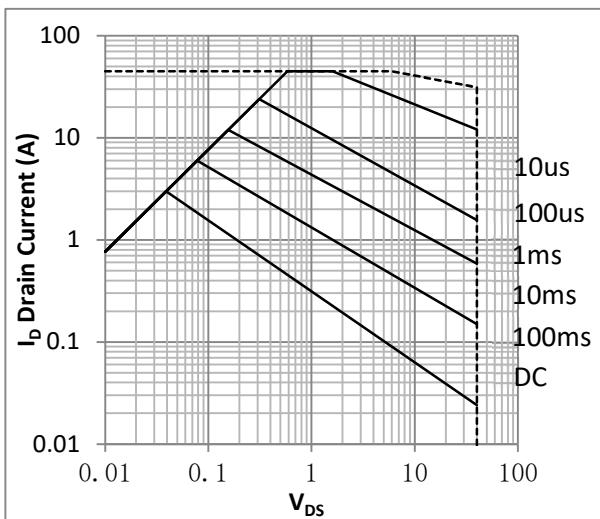


Figure 11. Gate-to-Source and  
Drain-to-Source Voltage vs. Total Charge

Fig.12 Capacitance Variation

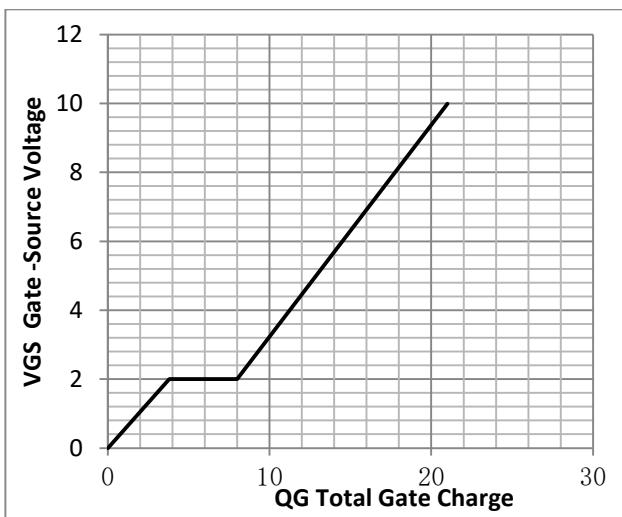


Fig.13 Switching Time Measurement Circuit

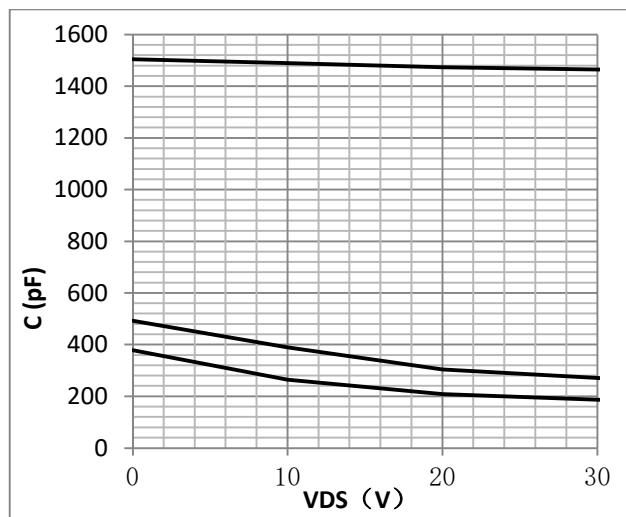


Fig.14 Gate Charge Waveform

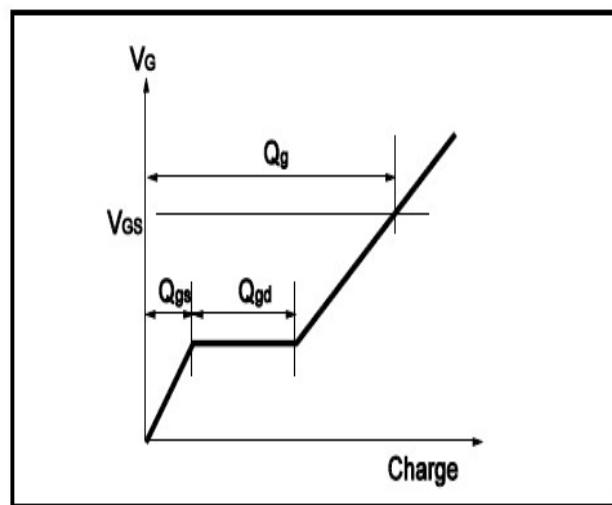
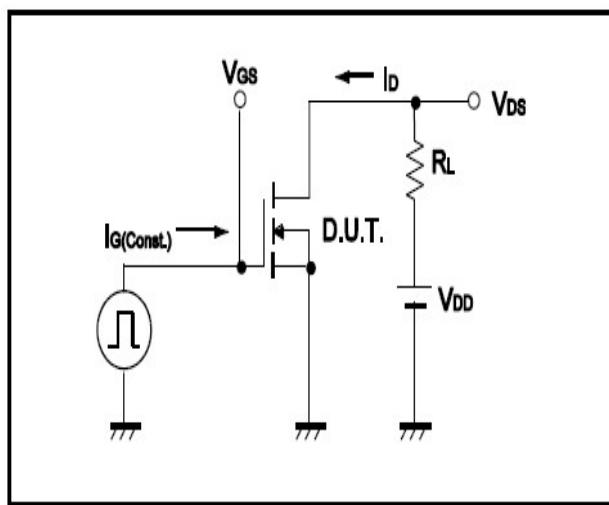




Fig.15 Switching Time Measurement Circuit

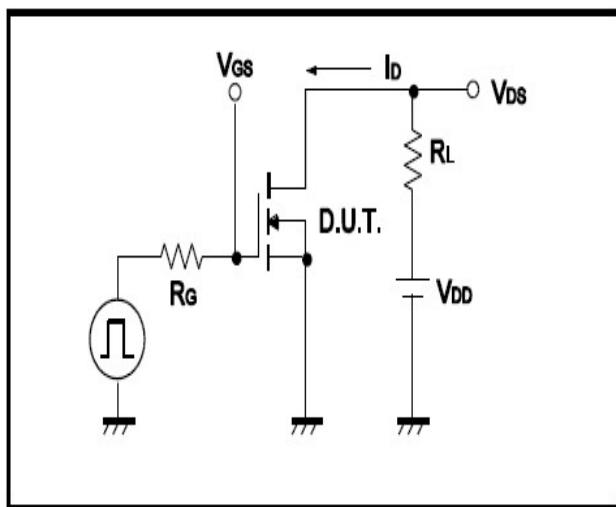


Fig.16 Gate Charge Waveform

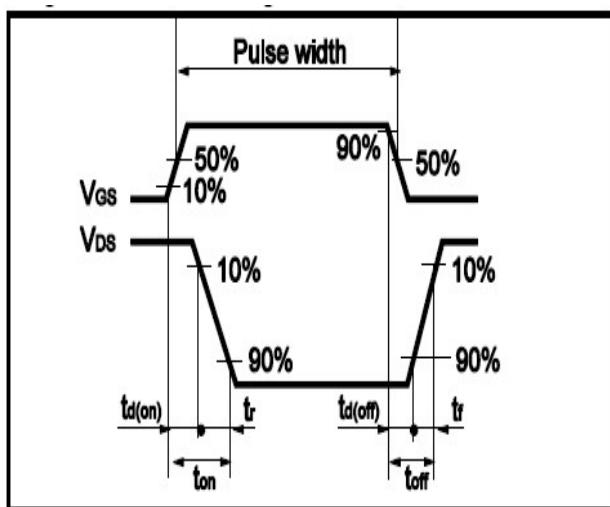


Fig.17 Avalanche Measurement Circuit

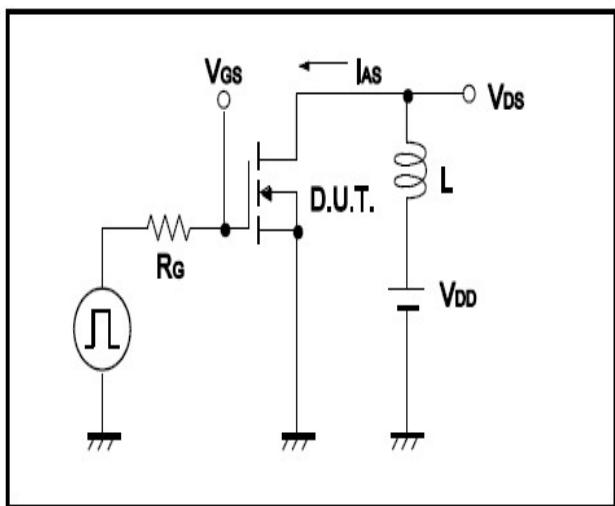
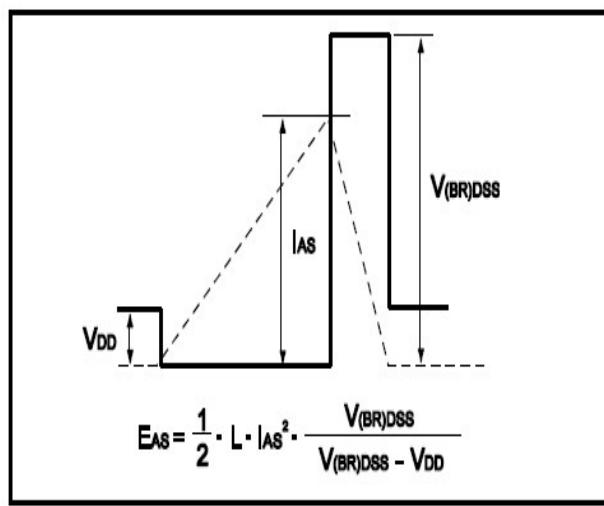


Fig.18 Avalanche Waveform





## •Dimensions (DFN3x3)

Unit: mm

